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P/1805-17

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

New York, New York

Markus Turtinen, et al.

Date: December 18, 2006

Serial No.: 10/526,831

Group Art Unit: 2856

Filed: July 20, 2005

Examiner: ---

For: CHARACTERISATION OF PAPER

Commissioner for Patents
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Alexandria, VA 22313-1450

SUBMISSION

Sir:

Submitted herewith is a copy of art together with a form listing the same for the convenience of the Examiner.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents P.O. Box 1450, Alexandria, VA 22313-1450, on December 18, 2006

Respectfully submitted,

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Name of applicant, assignee or
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Signature

December 18, 2006

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Enclosures

APPLICANT'S ART CITATION (Use several sheets if necessary)		Application 10/526,831		OFGS File No. P/1805-17		
		Applicant Markus Turtinen, et al.				
		Filing Date July 20, 2005		Group Art Unit 2856		
U.S. PATENT DOCUMENTS (not submitted for applications filed after 6/30/03)						
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					
FOREIGN PATENT DOCUMENTS						
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation Yes No
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
		Jukka Iivarinen (2000) Surface Defect Detection with Histogram-Based Texture Features, Helsinki University of Technology, Laboratory of Computer and Information Science.				
		Jukka Iivarinen, et al. (1998) An Adaptive Texture and Shape Based Defect Classification, Pattern Recognition, Proceedings, PP. 117-122.				
		Timo Ojala, et al., Gray Scale and Rotation Invariant Texture Classification with Local Binary Patterns, IEEE Transactions on Pattern Analysis and Machine Intelligence, Vol. 24, No. 7.				
Examiner		Date Considered				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.						